 Searc	h Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/913,454	CHEN ET AL.	
Examiner	Art Unit	
Minh Dieu Nauven	2137	

	SEAR	CHED	
Class	Subclass	Date	Examiner
713	1-2, 100	1/3/2006	MDN
726	26	1/3/2006	MDN
380	155	1/3/2006	MDN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
-			
-			
ļ	1		
	F		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Updated text and class search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	1/3/2006	MDN